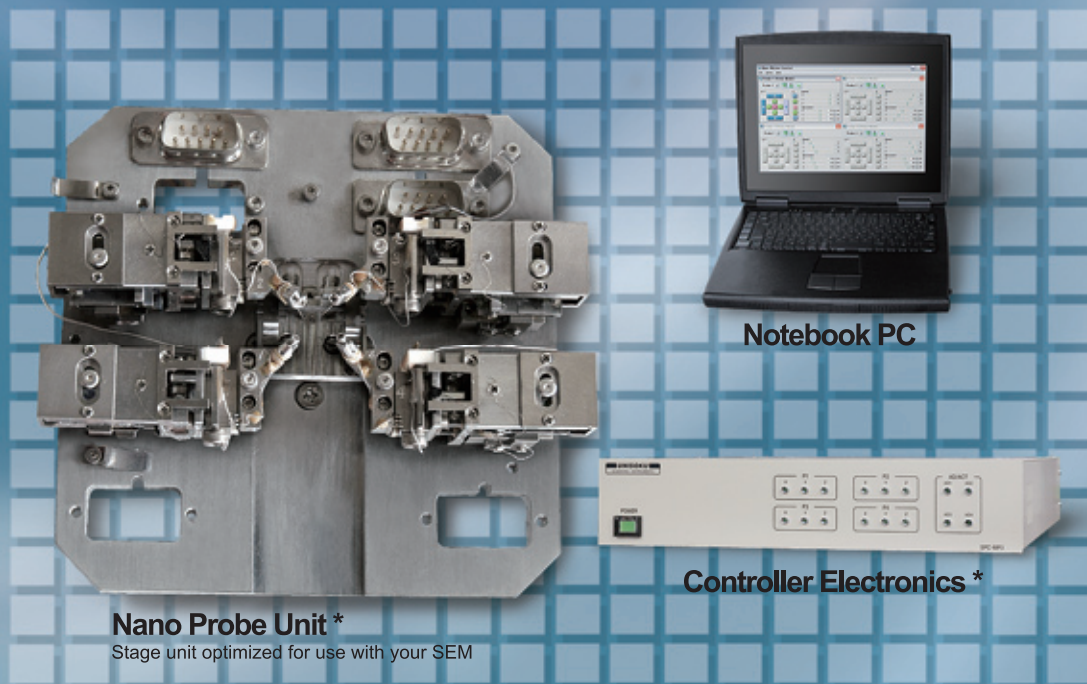


Nano-probe Electrical Measurement System

UMP-1000

The model UMP-1000 is an analyzer specially designed for the local electrical properties of the sample surface, nano-devices, etc. This system can be installed on any SEM stages. Independently, each probe is able to produce extremely fine position changes (XYZ) down to nanometer range.



Nano Probe Unit *
Stage unit optimized for use with your SEM

Notebook PC

Controller Electronics *

Features

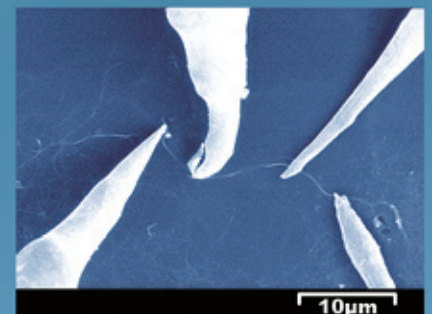
- So compact and light multi-probe unit that can be installed on any SEM stages.
- Easy to control using notebook PC.
- Suitable for Ultrahigh-Vacuum applications.
- Unlimited resolution to produce precise positioning.

Options

- SPM (STM, AFM, etc.) Function
- Bending / Tensile Strength Test Attachment
- Sample Stage Positioning Sample Heating / Cooling
- The Number of Probe (add / decrease)
- Combine with Ultrahigh Vacuum System

Example of Use

- Measurement of electrical property
- Manipulation on nano-scale



Four probes over carbon nanotube
*Contribution by Prof. Sumiyama,
Nagoya Institute of Technology.*

Specifications

Nano Probe Unit

XY Range

Coarse	± 2.5 mm in 150 nm steps
Fine	$\leq 1\mu\text{m}$ in 10 nm* steps

Z Range

Coarse	± 1.5 mm in 150 nm steps
Fine	$\leq 1\mu\text{m}$ in 10 nm* steps

Sample Size 10 mm X 10 mm X 1 mm

Weight $\leq 1000\text{g}$

* 0.1nm resolution is possible with optional software.

$\phi 31\text{mm}$
(fit the requirement of SEM)

Typical nano probe stage unit are shown above.
The stage unit is fabricated to fit your SEM system. Ask for details.

SEM Image of 4 probes

Instrumental components subject to change without prior notice for improvement in performance.

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